



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. .... 10/803,264  
Filing Date ..... March 17, 2004  
Inventor..... Warren M. Farnworth et al.  
Assignee..... Micron Technology, Inc.  
Group Art Unit..... 2829  
Examiner ..... Russell M. Kobert  
Attorney's Docket No. .... MI22-2524  
Customer No.. .... 021567  
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and  
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

**RESPONSE TO JANUARY 31, 2006 FINAL OFFICE ACTION**  
**PURSUANT TO 37 C.F.R. §1.116**

To: Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

From: D. Brent Kenady  
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Responsive to the January 31, 2006 Final Office Action, Applicant amends and  
remarks as follows:

**AMENDMENTS**

Underlines indicate insertions and ~~strikeouts~~ indicate deletions.

07/05/2006 RMEBRAHT 00000024 10803264

01 FC:1252  
02 FC:1201  
03 FC:1202

~~450.00 OP~~  
200.00 OP  
50.00 OP

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